



ALTERNATIVE TO PTO/SB/08A/B (09/06)

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/713,754
				Filing Date	November 13, 2003
				First Named Inventor	Bruce W. MCGAUGHY
				Art Unit	2123
Sheet	1	of	1	Examiner Name	A. Pierre-Louise
				Attorney Docket Number	188122001900

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
APL	1.	US-2003/0237067-A1	12-25-2003	Mielke et al.	
APL	2.	US-2004/0078767-A1	04-22-2004	Burks et al.	
APL	3.	US-4,942,536-A	07-17-1990	Watanabe et al.	
APL	4.	US-6,026,226-A	02-15-2000	Heile et al.	
APL	5.	US-6,035,107-A	03-07-2000	Kuehlmann et al.	
APL	6.	US-6,301,687-B1	10-09-2001	Jain et al.	
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APL	9.	US-6,449,761-B1	09-10-2002	Greidinger et al.	
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APL	11.	US-6,865,525-B1	03-08-2005	Zhong	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>2</sup> -Number <sup>3</sup> -Kind Code <sup>4</sup> (if known)				

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	12.	Chakrabarti, D.R. et al. (November 23-24, 1995). "An Improved Hierarchical Test Generation Technique for Combinational Circuits with Repetitive Sub-circuits," <i>Proceedings of the Fourth Asian Test Symposium 1995</i> , 1:237-243.	
	13.	Jones et al. (February 1994). "A Cache-Based Method for Acceleration Switch-Level Simulation," <i>IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems</i> 13(2).	
	14.	Stanford.edu. "Radix 2 FFT Complexity is N Log N," <i>In Mathematics of the Discrete Fourier Transform (DFT) with Music and Audio Application</i> . Smith, III, J.O. (2003). W3K Publishing. Stanford, located at < <a href="http://ccma.stanford.edu/~jos/mdft/Radix_2_FFT_Complexity.html">http://ccma.stanford.edu/~jos/mdft/Radix_2_FFT_Complexity.html</a> >, 1 page.	
	15.	Wong, Y. (1985). "Hierarchical Circuit Verification," <i>IEEE 22<sup>nd</sup> Design Automation Conference</i> .	

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Examiner Signature		Date Considered	7/21/2007
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